TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

TA8061H

DUAL HIGHSIDE DRIVER WITH DIAGNOSIS

The TA8061H is a 1.5A highside driver containing two circuits. Each circuit has a self-diagnostic function which produces a diagnostic output. The input is TTL-compatible. This IC has other various protective functions

FEATURES

• Output current capacity: 1.5A

• Diagnostic function : Load-open (10mA or less) and

over-current (3A or more) detection

• Protective function : Short-circuit protection (latch) and

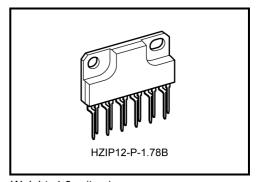
thermal-shutdown / over-voltage

protection (nonlatch)

• Low standby current : 0.5mA (max.)

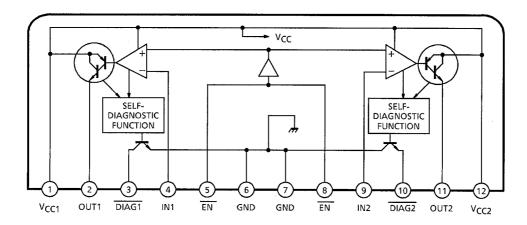
Two circuits contained

• Power package HZIP-12pin



Weight: 4.0 g (typ.)

BLOCK DIAGRAM AND PIN LAYOUT



PIN DESCRIPTION

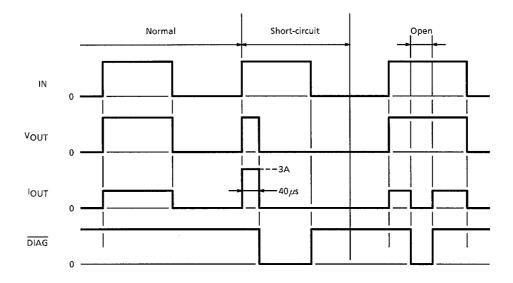
PIN No.	SYMBOL	DESCRIPTION			
1, 12	V _{CC}	Power supply pin. A function for protection against over-voltage is provided so that the output will turn off when the applied voltage exceeds 27.5V (Typ.). This function works to protect the IC and load.			
2, 11	OUT	PNP-type complementary output pin with a current capacity of 1.5A. When the output pin is supplied with a current exceeding the detection current (typically 3A) because of load short-circuit, the output is latched to the OFF state to protect the IC. To restart, turn off the input once, then raise it high.			
3, 10	DIAG	Self-diagnosis detection pin. This signal goes low when the output is short-circuited or opened while the input is on (high). The output will be latched when the load is short-circuited, but will not when the load is opened. This pin supplies an NPN open-collector output.			
4, 9	IN	TTL-compatible input pin. The circuit is shown as follows. $ \frac{47k\Omega}{9} $			
5, 8	ĒN	When this signal goes high, both channels 1 and 2 are placed in standby state (0.5mA Max.).			
6, 7	GND	Grounded.			

2

TRUTH TABLE

IN		DIAG		
Н	H (ON)	Normal	Н	
		Abnormal	L	
L	L (OFF)	_	Н	

TIMING CHART



MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Power Supply Voltage	V_{CC}	30	٧	
Tower Supply Voltage	V _{CC}	60 (1s)		
Input Voltage	V _{IN}	18	٧	
Output Voltage	V _{OUT}	-0.3~V _{CC}	٧	
Output Current	l _{OUT}	1.5	Α	
Power Dissipation	P_{D}	25	W	
Operating Temperature	T _{opr}	-40~110	°C	
Storage Temperature	T _{stg}	-55~150	°C	
Lead Temperature time	T _{sol}	260 (10s)	°C	

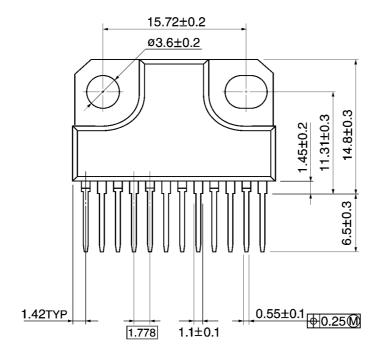
ELECTRICAL CHARACTERISTICS (V_{CC} = 12V, Ta = 25°C)

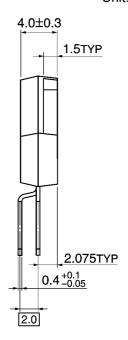
CHARACTERISTIC	SYMBOL	PIN	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
		V _{CC1, 2}	_	In standby state	_	_	0.5	- mA
Power Supply Current	I _{CC}		_	EN = "L" IN = "L"	_	4	8	
Tower Supply Current			_	CH1 or CH2 = ON	_	20	40	
			_	CH1, CH2 = ON	_	35	60	
Input Voltage	V _{IH}	- IN1, 2	_		2	_	_	V
input voitage	V _{IL}		_		-0.3	_	0.8	
Input Current	I _{IH}	- IN1, 2	_	V _{IN} = 3V	_	_	0.12	- mA
Imput Current	lıL		_	V _{IN} = 0.8V	_	_	0.03	
Output Voltage	V _{OH}	OUT1, 2	_	I _{OUT} = 1A	_	1.2	1.5	V
Output Voltage	V _{OL}	DIAG1, 2	_	I _{OUT} = 3mA	_	0.2	0.5	
Output Leakage Current	l. =	OUT1, 2	_	V _{OUT} = 0V	_	_	10	μА
Output Leakage Current	ILEAK	DIAG1, 2	_	V _{OUT} = 5V	_	_	10	
Over-current Detection	I _{SD1}	OUT1, 2	_		_	3.0	_	Α
Load-Open Detection	I _{SD2}	OUT1, 2	_		_	25	_	mA
Over-voltage Detection	V _{SD}	V _{CC1, 2}	_		_	27.5	_	V
Shutdown Temperature	T _{SD}		_			150	_	°C
Transfer Delay Time	t _{pLH}	OUT1, 2	— I _{OUT} = 1A	Ιουπ = 1Δ		1		μs
Transici Delay Time	t _{pHL}	3011, 2			5	_	μδ	

PACKAGE DIMENSIONS

HZIP12-P-1.78B

Unit: mm







Weight: 4.0g (Typ.)

5 2002-02-27

RESTRICTIONS ON PRODUCT USE

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